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 Phone: (202) 638-6666

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

APPLICANT: Carsten FALTUM, et al.GROUP ART UNIT: Not Yet AssignedSERIAL NO.: 10/501,911ATTY. DOCKET NO.: P69949US0FILING DATE: July 26, 2004TODAY'S DATE: September 27, 2004

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE (If Appropriate)
RTE	AA	4,882,245	11/21/89	Gelorme et al.			06/12/87
	AB	5,156,810	10/20/92	Ribi			06/15/89
	AC	5,482,678	01/09/96	Sittler			11/10/94
	AD	5,907,095	05/25/99	Lin			05/30/97
	AE	5,986,262	11/16/99	Volcker			01/21/98
	AF	6,016,686	01/25/00	Thundat			03/16/98
	AG	6,237,399	05/29/01	Shivaram et al.			01/15/99
V	AH	6,254,872	07/03/01	Yamamoto			02/18/98
RTE	AI	6,289,717	09/18/01	Thundat et al.			03/30/99

FOREIGN PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	Translation	
							(Yes)	(No)
RTP	AJ	0 072 744	02/23/83	EP				
	AK	96/31557	10/10/96	WIPO				
	AL	0 809 106	11/26/97	EP				
	AM	0 854 350	07/22/98	EP			✓	
	AN	98/50773	11/12/98	WIPO				
	AO	99/38007	07/29/99	WIPO				
	AP	00/36419	06/22/00	WIPO				
	AQ	00/58729	10/05/00	WIPO				
V	AR	00/66266	11/09/00	WIPO				
RTE	AS	2001183389	07/06/01	JP			Abstract	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

RTE	AT	O'Shea, S.J., et al., "Atomic force microscopy stress sensors for studies in liquids" J. Vac. Sci. Technol. B 14(2) Mar/Apr 96, pp. 1383-1385
RTE	AU	Berger, R., et al., "Micromechanics: A Toolbox for Femtoscale Science: "Towards a Laboratory on a Tip", Microelectronic Engineering 35, (1997) pp. 373-379

EXAMINER	<i>Rodney Lee</i>	DATE CONSIDERED	<i>June 25, 2005</i>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

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	BA						
	BB						
	BC						
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	BF						
	BG						
	BH						
	BI						
	BJ						
	BK						

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							(Yes)	(No)
RTP	BL	03/022731	03/20/03	WIPO				
RTP	BM	03/044530	05/30/03	WIPO				
RTP	BN	03/062135	07/31/03	WIPO				
	BO							
	BP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

RTP	BQ	Berger, R. et al., "Surface Stress in the Self-Assembly of Alkanethiols on Gold", Science, Vol. 276, June 1997, pp. 1942, 1945, 2021-2024
RTP	BR	Boisen, A., et al., "Environmental Sensors Based on Micromachined Cantilevers with Integrated Read-Out", Ultramicroscopy, 82, 2000, pp. 11-16
RTP	BS	Thaysen, J., "Atomic Force Microscopy Probe with Piezoresistive Read-Out and a Highly Symmetrical Wheatstone Bridge Arrangement", Sensors and Actuators 83, 2000, pp. 47-53

EXAMINER	<i>Rocky Liu</i>	DATE CONSIDERED	June 25, 2005
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